

Application/Control No.	Applicant(s)/Patent under Reexamination
10/773,668	KEIM ET AL.
Examiner	Art Unit

3661

CUONG H. NGUYEN

SEARCHED					
Class	Subclass	Date	Examiner		
701	51	4/11/2007	CHN		
239	585.2,585.	4/11/2007	CHN		
239	585.5	4/11/2007	CHN		
137	625	4/11/2007	CHN		

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
701	51	4/12/2007	CHN		
239	585.2,585	4/11/2007	CHN		
91	459	4/11/2007	CHN		
G05D	3 1/30 16/20 51/00	4/12/2007	CHN		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
WEST/DERWENT on allowable subject matter and IDS references	4/11/2007	CHN		
IEEE Xplore	4/11/2007	CHN		
Dialog DataStar	4/11/2007	CHN		
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